Introduction

Managers of manufacturing test organizations face wide and varied challenges spanning business, technical, and people management domains. Yet the test management problem set is often overlooked in test conferences and publications. This panel presents a unique opportunity for test managers to reveal, discuss, and brainstorm solutions to the key, and sometimes controversial, problems that they each face today. Test and DFT engineers will appreciate this chance to gain insight into management thinking and what drives the decision-making process.

Issues to be Addressed

- Balancing technical and economic tradeoffs. For example, the cost of test is remaining fixed in comparison to decreasing die cost. Why not outsource test 100%?
- What factors drive tester selection? A few years ago, it was simply raw tester speed. Now, power is a top issue. Will it continue? What do you want to pay for a tester 5 years from now? What is the tester HW and SW configuration?
- Standardization - Test organizations are required to support multiple test platforms, peripherals, and customers. How do we standardize test data, test data storage, test program generation, tester and test peripheral SW control to operate efficiently?
- Resources - How do we recruit and retain people with test skills? Why aren't students taught about test and design-for-test in college? How can we affect that? How do we develop test skills? What are the key skills of a good test engineer?
- Design-For-Test - How can manufacturing test managers enable DFT? How is a tighter coupling between test and designers achieved? Is it possible? Organizational re-structuring? Education? What is the economic or Time-to-Market impact?

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